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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10053373	FILING DATE 10/24/2001	CLASS 378	SUBCLASS	GAU 2832	EXAMINER
**APPLICANTS: Fanton Jeffrey; Uhrich Craig; Koppel Louis;					
**CONTINUING DATA VERIFIED: THIS APPLN CLAIMS BENEFIT OF 60/261,154 01/11/2001					
** FOREIGN APPLICATIONS VERIFIED:					
PG-PUB <input type="checkbox"/> DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>			
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no		35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no		ATTORNEY DOCKET NO TWI-13310	
Verified and Acknowledged Examiners's initials					
TITLE : X-ray reflectance measurement system with adjustable resolution					
U.S. DEPT. OF COMM./PAT. & TM.-PTO-435L (Rev. 12-94)					

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED		
			Total Claims	Print Claim for O.G.	
ISSUE FEE		Primary Examiner	DRAWING		
Amount Due	Date Paid		Sheets Drwg.	Figs. Drwg.	Print Fig.
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE	Application Examiner		
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